

<b>Notice of References Cited</b>	Application/Control No. 10/625,733	Applicant(s)/Patent Under Reexamination NITTA ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0148559	08-2003	Onishi et al.	438/138
	B	US-2003/0132450	07-2003	Minato et al.	257/110
	C	US-2002/0025632	02-2002	Hayashi et al.	438/275
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 452817	10-1991	European	Sawada et al	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.